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Semiconductor devices - Micro-electromechanical devices -Part 20: Gyroscopes (standards.iteh.ai)

Dispositifs à semiconducteurs – Dispositifs microélectromécaniques – <u>IEC 62047-20:2014</u> Partie 20: Gyroscopes fl4ca691f062/iec-62047-20-2014





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SEMICONDUCTOR DEVICES – MICRO-ELECTROMECHANICAL DEVICES –

Part 20: Gyroscopes

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International Standard IEC 62047-20 has been prepared by subcommittee 47F: Microelectromechanical systems, of IEC 47: Semiconductor devices.

The text of this standard is based on the following documents:

FDIS	Report on voting				
47F/188/FDIS	47F/191/RVD				

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

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SEMICONDUCTOR DEVICES – MICRO-ELECTROMECHANICAL DEVICES –

Part 20: Gyroscopes

1 Scope

This part of IEC 62047 specifies terms and definitions, ratings and characteristics, and measuring methods of gyroscopes.

Gyroscopes are primarily used for consumer, general industries and aerospace applications. MEMS and semiconductor lasers are widely used for device technology of gyroscopes.

Hereafter, gyroscope is referred to as gyro.

2 Normative references

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

(standards.iteh.ai)

None

IEC 62047-20:2014https://standards.iteh.ai/catalog/standards/sist/e10d7ee4-6d1b-409b-861e-3 Terms and definitionsf14ca691f062/iec-62047-20-2014

For the purposes of this document, the following terms and definitions apply.

3.1 rotating table rate table

rotating tool on which a gyro is loaded during measurement

3.2

earth rate

angular rate generated in inertial space due to the rotation of the earth

Note 1 to entry: When the angular rate in inertial space is defined as stellar day 23 hours, 56 minutes, a reference of 4,098 903 691 seconds is obtained as specified by the International Earth Rotation and Reference Systems Service (IERS) and therefore, the angular rate of Earth in inertial space is approximately 15,04 °/h. For details of the definition, refer to the IERS website (http://www.iers.org).

3.3

scale factor

ratio of gyro output voltage or output digital signal versus the rotating angular rate being applied, described in unit: V/(°/s) or bit/(°/s)

4 Essential ratings and characteristics

4.1 Categorization of gyro

Table 1 shows uses of gyro categorized by application fields.

Category	Contents
1	primarily for consumer use where variations of bias are not specified
2	primarily for industrial use where designing with appropriate range of values of variations of bias
3	primarily for aerospace use where designing with detectable function of the earth rate

Table 1 – Categories of gyro

4.2 Absolute maximum ratings

Table 2 describes absolute maximum ratings of gyro.

The following items listed in the table shall be described in the specification, unless otherwise stated in the relevant procurement specifications. Stresses over these limits can be one of the causes of permanent damage to the devices.

Item no	Absolute	C	atego	ory	Spe	Specification		Unit	Remarks
	ratings	1	2	3	min	typ	max		
4.2.1 4.2.2	Storage temperature range Operating	× Fe	×	× ST	x AN	DA	×	°C PF	REVIEW
	temperature range			(st	and	lar	ds.i	teh	.ai)
4.2.3	Storage humidity range <u>https:/</u>	'star	idards	.iteh.a fl	<u>IE</u> i/catalo ₂ 4ca691	<u>C 620</u> g/stano 1062/ie	<u>47-20:2</u> lards/sis ec-6204	% <u>014</u> t/e10d7	Moisture absorption management level (for example, see levels specified in Table 5-1 "Moisture Sensitivity Levels" of page 7 in PC/JEDEC J-STD-020C, [1] ¹) for reflow soldering shall be specified. Those descriptions shall not be provided to devices applied with no reflow soldering process and/or hermetic seal packaging process.
4.2.4	Mechanical shock in operating state	х	x	х			x	m/s ²	Maximum limiting value of mechanical shock which does not cause permanent damage to devices under an appropriate operating state. Acceleration, times and wave forms shall be specified.
4.2.5	Mechanical shock in non operating state	х	x	x			x	m/s ²	Maximum limiting value of mechanical shock which does not cause permanent damage to devices under an appropriate non-operating state. Acceleration, times and wave forms shall be specified.
4.2.6	Mechanical vibration in operating state	x	x	x			х	m/s²	Maximum limiting value of mechanical vibration acceleration and frequency which does not cause permanent damage to devices under an appropriate operating state.
4.2.7	Mechanical vibration in non operating state	х	x	x			x	m/s²	Maximum limiting value of mechanical vibration acceleration and frequency which does not cause permanent damage to devices under an appropriate non-operating state.
4.2.8	Angular rate limit	x	x	х			x	°/s	Maximum limiting value of angular rate which does not cause permanent damage to devices under an appropriate operating state.

Table 2 – Absolute maximum ratings

¹ Numbers in square brackets refer to the Bibliography.

Item no	Absolute	C	ateg	ory	Specification			Unit	Remarks
	maximum ratings		2	3	min	typ	max		
4.2.9	Angular acceleration limit	x	x	x			x	°/s²	Maximum limiting value of angular acceleration which does not cause permanent damage to devices under an appropriate operating state.
4.2.10	Maximum supply voltage	x	x	x			х	V	Maximum limiting value of supply voltage which does not cause permanent damage to devices.
4.2.11	Maximum supply current						x	A	Maximum limiting value of supply current which does not cause permanent damage to devices. This limiting value shall be specified only for a kind of constant current driving devices.
NOTE x: mandatory, blank: optional									

4.3 Normal operating rating

Table 3 describes normal operating ratings of gyro.

The following items should be described in the specification, unless otherwise stated in the relevant procurement specifications. These conditions are recommended to keep specified characteristics in stable state during operations of applying devices.

ltem no.	Normal operating	Cat	ego	ry.	620 4 7-	ecificat	ion	Unit	Remarks
	https://standards.it	eh.ai/o	ca 2 a	03 /9	ta min rd	s/type1	0 māx -4	-6d1b-4	409b-861e-
4.3.1	Guarantee operating temperature range	f l 40	a 6 9	1 f 0	62/iec-6	2047-2	0-2 0 14	°C	
4.3.2	Guarantee operating humidity range	x	x	х			x	%	
4.3.3	Supply voltage range	х	х	х	х	х	х	V	
4.3.4	Current consumption	х	х	х			х	А	
4.3.5	Start up current			х			х	А	
4.3.6	Power supply ripple requirement			х			x	Vpp	
4.3.7	Other environmental condition				x		x		Recommended ranges of appropriate indexes of environmental conditions (such as conditions of electromagnetic environments, air pressure) specified as a specified minimum value to maximum value.
4.3.8	Overload recovering time			x			х	S	Maximum value of overload recovering time in the range of measurement less than maximum rating.
NOTE x:	NOTE x: mandatory, blank: optional								

Table 3 - Normal operating ratings

4.4 Characteristics

Table 4 describes characteristics of gyro.

– 8 –

Item	Characteristics	Category		Specification			Unit	Remarks	
no		1	2	3	min	typ	max		
4.4.1	Measurement range	x	x	x			x	°/s	Angular rate measuring range for guarantee of performance
4.4.2	Nominal scale factor	x	x	x		x		V/(°/s) or	Nominal scale factor is also called as standard sensitivity.
								bit/(°/s)	
4.4.3	Initial scale factor variation		x	x	x		x	%	Minimum and maximum value of variation from standard sensitivity at a specified temperature
4.4.4	Scale factor variation with temperature or Temperature coefficient of scale factor		x	x	x		x	%	Minimum and maximum value of standard sensitivity under a specified variation in temperature
4.4.5	Ratiometric error for scale factor			x			x	%	Maximum value of error of sensitivity applying voltage fluctuation caused by operating instability of applying electric power supply
4.4.6	Linearity						х	%	
4.4.7	Scale factor stability	re h	S	TĂ	NI	DÅI	RD	PREV	A typical value of stability of sensitivity under a specified definite input voltage value
4.4.8	Scale factor symmetry	n	(sta	nd	ard	ls.it	eh.ai)	A typical value of asymmetry of sensitivity defined as a ratio of the sensitivity applying plus value of a
	https://s	tanda	rds.ite	h.ai/c fl4c	<u>IEC</u> atalog/ a691f0	<u>62047</u> standar 62/jec-	<u>-20:20</u> ds/sist/ 62047	<u>14</u> e10d7ee4-6o -20-2014	specified input voltage to minus value of a specified input voltage, see 5.1.3.8.
4.4.9	Cross axis sensitivity			X	u07110	02/100-	x	%	Maximum value of sensitivity of cross axis (see 5.2.3 Principle of measurement).
4.4.10	Nominal bias	x	x	x		x		V or bit	Typical value of bias voltage or bit value under an appropriate applying input voltage value
4.4.11	Initial bias variation			x	x		x	°/s	Minimum and maximum value of bias under a specified temperature
4.4.12	Bias variation with temperature or Temperature coefficient of bias			x	x		x	°/s	Minimum and maximum value of standard bias under a specified variation in temperature
4.4.13	Ratiometric error for bias			x			x	V	Maximum value of error of bias applying voltage fluctuation caused by operating instability of applying electric power supply. No description is required for digital output case.
4.4.14	Bias repeatability (switch on to switch off)			x	x		x	°/s	Minimum value and maximum value of bias fluctuation of each period during a switching on state to a switching off state
4.4.15	Bias hysteresis			x			×	°/s	Maximum value of hysteresis of bias under a specified variation in temperature
4.4.16	Linear g sensitivity			x			x		Maximum value of changed bias value under operating conditions of a specified constant acceleration value, expressed in comparison with $g((^{\circ}/s)/g)$

Table 4 – Characteristics

Item	Characteristics	Ca	atego	ry	Spe	cifica	tion	Unit	Remarks
no		1	2	3	min	typ	max		
4.4.17	Bias drift after power on			x			x	°/s	Maximum value of drift of bias during turned on state of applying electric power supply
4.4.18	In-band noise			x			×	°/s	In-band output noise at stable state operation, described with RMS
4.4.19	Broadband noise			x			x	°/s	Broadband output noise at stable state operation, described with RMS
4.4.20	Angular random walk			x			х	° /√h or (° /h)/√Hz	Output variation of gyroscope due to noise, described with RMS
4.4.21	Bias instability			х			x	°/s	Described with RMS
4.4.22	Start up time			x			x	S	Time required for the gyro output to reach the specified output after power on
4.4.23	Frequency band	х	х	х	x			Hz	Frequency response characteristics
4.4.24	Gain peak						x	dB	Maximum value of gain of frequency characteristics under a specified frequency. Describe with a specified value of the frequency (Hz).
4.4.25	Resolution	ſeł	S	TxA	NI		RD	PREV	Detectable minimum change in the input angular rate
NOTE	NOTE x: mandatory, blank: optional, Stancessary Os. iteh.ai)								

IEC 62047-20:2014https://standards.iteh.ai/catalog/standards/sist/e10d7ee4-6d1b-409b-861e-Measuring methodsf14ca691f062/iec-62047-20-2014

5.1 Scale factor

5

5.1.1 Purpose

To specify measuring method relating to scale factor in gyro.

5.1.2 Measuring circuit (circuit diagram)

Figure 1 shows an example of composition of the sensitivity measuring circuit and Figure 2 shows an example of wiring configuration. The measuring circuit is composed of the gyro to be measured and the devices listed below. Components to apply in the measuring circuit shall satisfy the points described below.

- Temperature controlled chamber: This should be capable of maintaining the gyro at a specified ambient temperature. Furthermore, the temperature control range should be wider than the operating temperature range of gyro.
- Temperature sensor: This should be capable of measuring the temperature in the temperature controlled chamber. A temperature sensor provided in advance in the temperature controlled chamber can be used.
- Power supply for gyro: This should be capable of supplying the voltage and current required by gyro. The fluctuating range for ripple voltage on the output should meet the gyro requirements in the supplying state.
- Data acquisition system: Measuring device or measuring system adjusted to the output configuration of gyro. For example, a digital multimeter or data logger is used if gyro output is analogue voltage.

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- Rotating table control device: Control device which controls the input angular rate given to the rating table. This table is given an angular rate of rotation that is not less than the detection range of gyro, and that is capable of accommodating changes in the angular rate corresponding to the minimum resolution. See Annex A for measurement accuracy of the rotating table.
- Measuring system controller: An overall system for automatic control of the power supply, gyro, data acquisition system and rotating table control device. This is not required for manual operation.
- Slip ring: It should be noted that the slip ring can be a source of noise generation.



Key

•	
1	DUT, a piece of gyro
2	rate table
3	temperature controlled chamber, to keep a specified temperature value of DUT
4	temperature sensor, to monitor environmental temperature in a chamber
5	power supply to operate DUT
6	data logger, to obtain data during the measurement
7	controller for rate table, to set up a specified rotating condition of the rate table
8	control system, to control the measuring circuit during the measurement
9	slip ring

Figure 1 – Example of measuring circuit



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Figure 2 – Example of wiring configuration

5.1.3 Measuring principle

5.1.3.1 Scale factor

In the measuring circuit shown in Figure 1, while gyro is under conditions of a specified measuring temperature T_{BASE} (specified temperature provided as a medium value between a specified minimum operating temperature and maximum operating temperature, see Figure 4) and a specified supply voltage V_{BASE} , rotating angular rate of $x_1, x_2, \dots, x_{2n+1}$, which divides lower and higher half detection range of gyro into *n*-distribution such as x_1, x_2, \dots, x_n (preferably $n \ge 5$) are applied, and corresponding output values of signal of $y_1, y_2, \dots, y_{2n+1}$ measured in unit of V/(°/s) or bit/(°/s) of this detection input angular rate.

Key

1

2 3

Х

 x_1

Y

 y_1

 y_{n+1}

 x_{n+1}

Furthermore, although the manufacturer can specify the value of n, it can be changed as necessary based on specifications agreed between a manufacturer and its user.

Figure 3 shows an example of the measurement data. Abbreviated symbols of CCW and CW in the figure show the left rotation (counter clockwise) and right rotation (clockwise), respectively. (In Figure 3, it is equally divided by n = 5 and a total of 11 points of data are shown including the stationary state). A scale factor is obtained by calculations from these points. However, since acquired data are not on a straight line as represented by Figure 3, a straight line on which the sum of squares becomes minimum is obtained by calculation (this straight line is referred to hereafter as the best fit line).



Figure 3 – Example of measurement data when the angular rate is applied

Here, the gyro output value at each measuring point is represented by " y_i " and the angular rate to be input to gyro is represented by " x_i ". Constants of the best fit line " $y = a_{BASE} \times x + a_$ b_{BASF} " are then obtained as follows:

$$a_{\text{BASE}} = \frac{(2n+1)\sum_{i=1}^{2n+1} x_i y_i - \sum_{i=1}^{2n+1} x_i \sum_{i=1}^{2n+1} y_i}{(2n+1)\sum_{i=1}^{2n+1} x_i^2 - \left(\sum_{i=1}^{2n+1} x_i\right)^2}$$
(1)